

CORNING

Tropel® UltraSort II

*A fully automated wafer flatness metrology platform
with customizable measurement components*

The UltraSort II is a flexible, high-throughput, fully automated platform that incorporates any Tropel wafer flatness measurement system, providing full surface bow, warp, TTV, and stepper simulation parameters as described in SEMI M1. The UltraSort II can also accept additional modules including additional cassettes, another interferometer, OCR, ROA, and many more. The system modularity allows you to get more value out of your automated wafer flatness inspection system. The UltraSort II platform is designed to enable full factory automation including SECS/GEM, GEM 300 host systems, along with other custom data export systems.



Key Specifications

CE Compliance

Semi S2/S8 Compliance

ISO 9001:2015, 9014:2015, 14001

Available Wafer Configurations

2"-6" Open Cassettes

4"-8" Open Cassettes

300mm FOUP

Throughput

FlatMaster clamped/unclamped

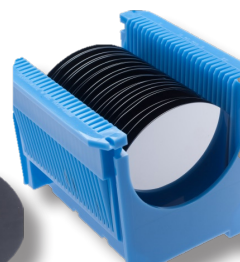
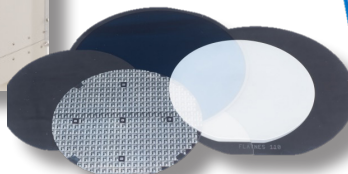
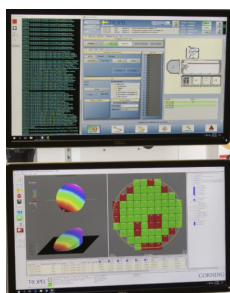
150 wph

FlatMaster clamped/unclamped/thickness

120 wph

FlatMaster MSP clamped/unclamped/thickness

60 wph



For more information about the UltraSort II or any other of our Tropel® Metrology Instruments, please contact:
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